

ABSTRACT

A probe storage jig has a structure in which a first guide plate and a second guide plate are stacked. A through-hole penetrating from an upper surface to a lower surface is formed in each of the first guide plate and the second guide plate. The probe storage jig holds the probe penetrating through the through-hole formed in each of the first guide plate and the second guide plate, in a state in which an upper part of the support section is exposed when viewed from above the probe storage jig and a tip end of a free end of the arm is exposed when viewed from below the probe storage jig. The probe storage jig is configured in such a way that the first guide plate and the second guide plate are movable so as to sandwich the probe between the first guide plate and the second guide plate.

FIG. 1